Deep Learning and Artificial Intelligence Winter School 2020 (DLAI4)

Robust Machine Learning for Reliable Deployment

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About Myself

My jobs:

- Director: RIKEN AIP
- Professor: University of Tokyo
- Consultant: several local startups



- Weakly-supervised learning,
- Robust learning,
- Transfer learning,
- Density ratio estimation,
- Reinforcement learning,
- Variational inference...

Academic activities:

 Program Chairs for NeurIPS2015, AISTATS2019, ACML2010/2020...



Sugiyama & Kawanabe, Machine Learning in Non-Stationary Environments, MIT Press, 2012



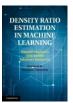
Sugiyama, Statistical Reinforcement Learning, Chapman and Hall/CRC, 2015

Sugiyama, Introduction to Statistical Machine Learning, Morgan Kaufmann, 2015

Cichocki, Phan, Zhao, Lee, Oseledets, Sugiyama & Mandic, Tensor Networks for Dimensionality Reduction and Large-Scale Optimizations, Now, 2017

Nakajima, Watanabe & Sugiyama, Variational Bayesian Learning Theory, Cambridge University Press, 2019

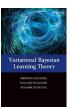












RIKEN Center for Advanced Intelligence Project (AIP)

- 10-year national project in Japan (2016-2025):
 - Develop next-generation AI technology (learning and optimization theory, etc.)
 - Accelerate scientific research (material, cancer, stem cells, genomics, etc.)
 - Solve socially critical problems (natural disaster, elderly healthcare, etc.)
 - Study of ethical, legal and social issues of Al (ethical guideline, privacy protection, etc.)
 - Human resource development (150+ researchers, 200+ students, 150+ interns, 300+ visiting scientists, 40+ industry projects)



Today's Topic: Robust Machine Learning

- In real-world applications, it becomes increasingly important to consider robustness:
 - Noise: sensor error, human error
 - Insufficient information: weak supervision
 - Bias: sample selection bias, changing environments
 - Attack: adversarial noise, distribution shift
- In this lecture, I will give an overview of our recent advances in robust machine learning.

http://www.ms.k.u-tokyo.ac.jp/sugi/publications.html

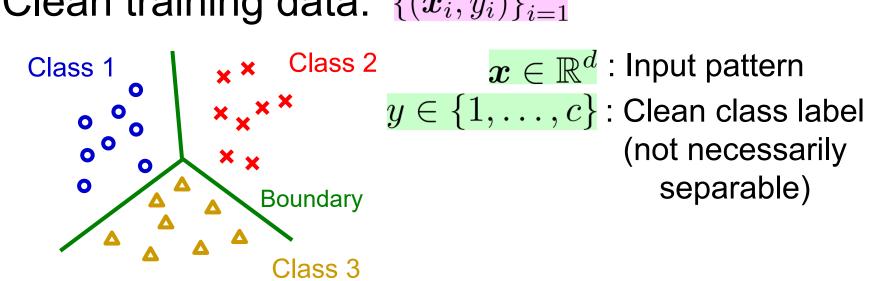


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- 1. Noisy label learning
- 2. Weakly supervised learning
- 3. Bias in training data
- 4. Noise in test input
- 5. Future outlook

Ordinary Classification

Clean training data: $\{(\boldsymbol{x}_i, y_i)\}_{i=1}^n$

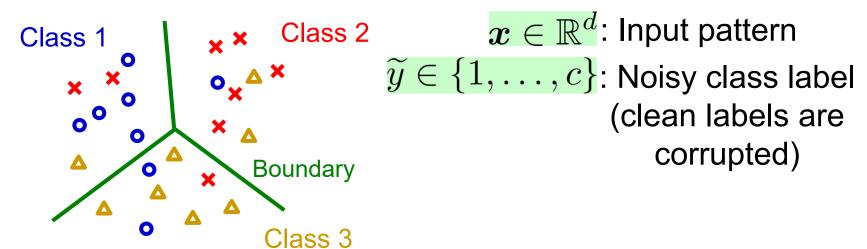


Training error minimization is statistically consistent and work well:

$$rac{1}{n}\sum_{i=1}^n \ellig(y_i,m{g}(m{x}_i)ig) \quad m{g}(m{x})\in\mathbb{R}^c$$
 : Classifier $\ell(y,m{g}(m{x}))\in\mathbb{R}$: Loss

Noisy Classification

Noisy training data: $\{(\boldsymbol{x}_i, \widetilde{y}_i)\}_{i=1}^n$

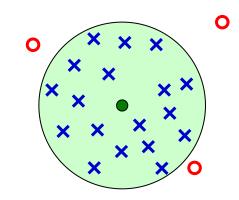


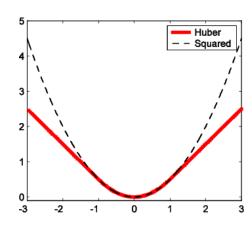
Training error minimization is no longer consistent and does not work well:

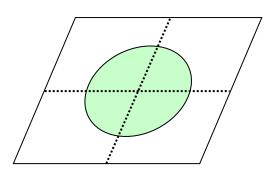
$$rac{1}{n}\sum_{i=1}^n \ellig(\widetilde{y}_i,m{g}(m{x}_i)ig) \quad m{g}(m{x})\in\mathbb{R}^c$$
 : Classifier $\ell(y,m{g}(m{x}))\in\mathbb{R}$: Loss

Standard Approaches

- Unsupervised outlier removal:
 - Substantially difficult
- Robust loss, regularization:
 - Not robust enough
- We want to go beyond the limitations of existing approaches!
 - Noise transition correction
 - Noiseless sample selection
 - Model capacity control







- Noise transition matrix *T*:
 - \bullet Flipping probability from y to \widetilde{y} .

_	1	0.1	0.5	
$T^{\perp} =$	0	0.8	0.5	\dot{y}
	0	0.1	0	

y

- Major approaches: Patrini et al. (CVPR2017)
 - ullet Loss correction by $oldsymbol{T}^{-1}$ to eliminate noise.
 - ullet Classifier correction by $oldsymbol{T}$ to simulate noise.
- We want to estimate T only from noisy data:
 - ullet Use human cognition as a "mask" for $oldsymbol{T}$.

Han, Yao, Niu, Zhou, Tsang, Zhang & Sugiyama (NeurlPS2018)

ullet Learn T and a classifier simultaneously.

Xia, Liu, Wang, Han, Gong, Niu & Sugiyama (NeurlPS2019)

ullet Decompose T into simpler components.

Yao, Liu, Han, Gong, Deng, Niu, Sugiyama & Tao (NeurlPS2020)

ullet Extension to input-dependent noise $oldsymbol{T}(oldsymbol{x})$.

Xia, Liu, Han, Wang, Gong, Liu, Niu, Tao & Sugiyama (NeurIPS2020)

(1-2) Co-teaching

Memorization of neural nets:

Arpit et al. (ICML2017) Zhang et al. (ICLR2017)

- Stochastic gradient descent fits clean data faster.
- However, naïve early stopping does not work well.
- "Co-teaching" between two neural nets:
 - Teach small-loss data each other.

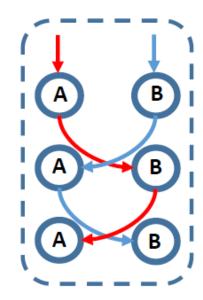
Han, Yao, Yu, Niu, Xu, Hu, Tsang & Sugiyama (NeurlPS2018)

Teach only disagreed data.

Yu, Han, Yao, Niu, Tsang & Sugiyama (ICML2019)

Gradient ascent for large-loss data.

Han, Niu, Yu, Yao, Xu, Tsang & Sugiyama (ICML2020)



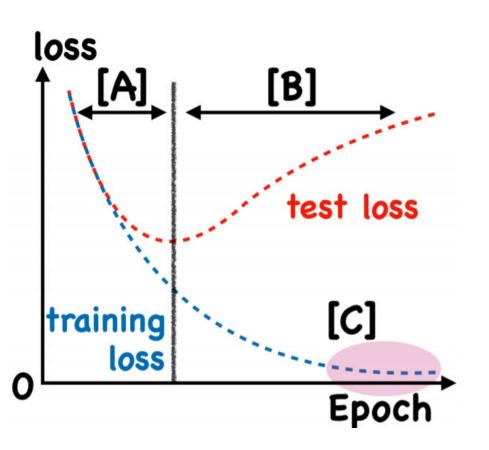
- No theory but very robust in experiments:
 - Works well even if 50% labels are randomly flipped.

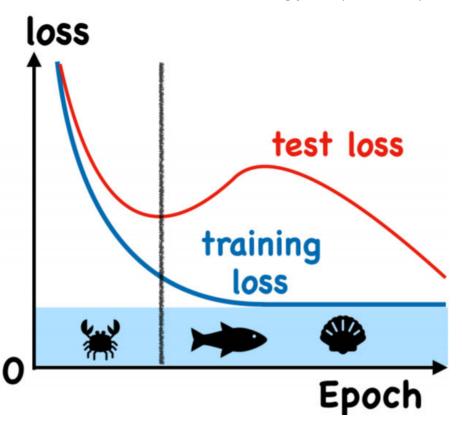
(1-3) Flooding

- Neural nets tend to overfit.
- "Flooding" the training error prevents overfitting.
 - It induces double descent?

$$|R(f) - b| + b$$

Ishida, Yamane, Sakai, Niu & Sugiyama (ICML2020)





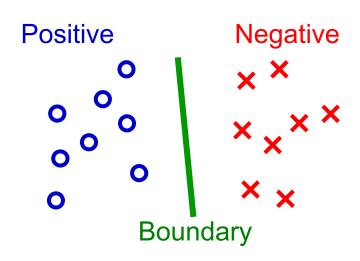


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Weakly Supervised Learning

- Ordinary supervised learning requires fully labeled data (input-output pairs).
- But collecting fully labeled data can be expensive in practice.
- Can we utilize "weakly" labeled data?
 - No negative data
 - Positive confidence data
 - Similar/dissimilar data
 - Complementary data
 - Partial-label data



P: Positive, N: Negative, U: Unlabeled

(2-1) PU Classification

- Only positive and unlabeled data is available; negative data is completely missing:
 - Click vs. non-click
 - Friend vs. non-friend
- We want to minimize the risk of classifier f only from PU data:

$$R(f) = \mathbb{E}_{p(\boldsymbol{x},y)} \left[\ell \left(y f(\boldsymbol{x}) \right) \right]$$

$$= \pi \mathbb{E}_{p(\boldsymbol{x}|y=+1)} \left[\ell \left(f(\boldsymbol{x}) \right) \right] + (1-\pi) \mathbb{E}_{p(\boldsymbol{x}|y=-1)} \left[\ell \left(-f(\boldsymbol{x}) \right) \right]$$

Risk for P data

Risk for N data

But N-risk cannot be estimated directly.

Key Trick

du Plessis, Niu & Sugiyama (NIPS2014, ICML2015) Niu, du Plessis, Sakai, Ma & Sugiyama (NIPS2016) Kiryo, du Plessis, Niu & Sugiyama (NIPS2017) Hsieh, Niu & Sugiyama (ICML2019)

Risk for P data

Risk for N data

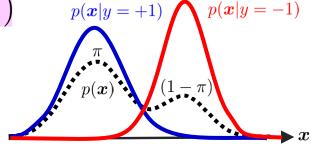
$$R(f) = \pi \mathbb{E}_{p(\boldsymbol{x}|y=+1)} \left[\ell \left(f(\boldsymbol{x}) \right) \right] + (1 - \pi) \mathbb{E}_{p(\boldsymbol{x}|y=-1)} \left[\ell \left(- f(\boldsymbol{x}) \right) \right]$$

■Use "U-density is mixture of P- and N-densities":

$$p(\mathbf{x}) = \pi p(\mathbf{x}|y = +1) + (1 - \pi)p(\mathbf{x}|y = -1)$$

Then

$$\pi = p(y = +1)$$



$$R(f) = \pi \mathbb{E}_{p(\boldsymbol{x}|y=+1)} \Big[\ell \Big(f(\boldsymbol{x}) \Big) \Big]$$

$$+\mathbb{E}_{\boldsymbol{p}(\boldsymbol{x})}\Big[\ell\Big(-f(\boldsymbol{x})\Big)\Big] - \pi\mathbb{E}_{\boldsymbol{p}(\boldsymbol{x}|\boldsymbol{y}=+1)}\Big[\ell\Big(-f(\boldsymbol{x})\Big)\Big]$$

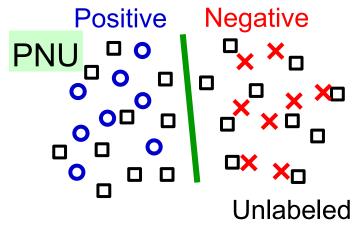
• Empirical risk minimization (ERM) is possible from PU data, just by replacing expectations by sample averages! $P(\widehat{\mathfrak{s}}) = P(\widehat{\mathfrak{s}}) = Q(\widehat{\mathfrak{s}}) \left(\frac{2\pi}{\pi} + \frac{1}{\pi} \right)$

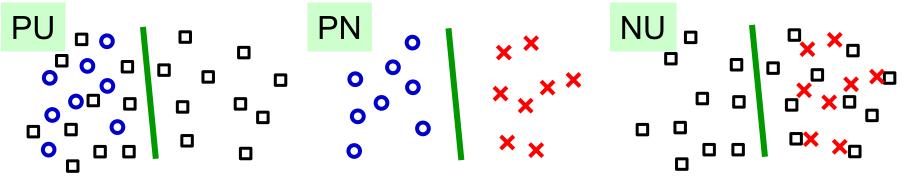
$$R(\widehat{f}_{\mathrm{PU}}) - R(f^*) \le C(\delta) \left(\frac{2\pi}{\sqrt{n_{\mathrm{P}}}} + \frac{1}{\sqrt{n_{\mathrm{U}}}}\right)$$

(2-2) PNU Classification (Semi-Supervised Classification)

Sakai, du Plessis, Niu & Sugiyama (ICML2017) Sakai, Niu & Sugiyama (MLJ2018)

- Let's decompose PNU into PU, PN, and NU:
 - Each is solvable.
 - Let's combine them!
- Without cluster assumptions, PN classifiers are trainable!





$$R_{0/1}(f) \le 2\widehat{R}_{\text{PN+PU}}^{\gamma}(f) + \mathcal{O}(1/\sqrt{n_{\text{P}}} + 1/\sqrt{n_{\text{N}}} + 1/\sqrt{n_{\text{U}}})$$

(2-3) Pconf Classification

Ishida, Niu & Sugiyama (NeurlPS2018)

- Only P data is available, even not U data:
 - Data from rival companies cannot be obtained.
 - Only positive results are reported (publication bias).
- "Only-P learning" is unsupervised.
- From positive-confidence data, ERM is possible!
 - Augment r-Pconf samples to (1-r)-Nconf samples.
 - Importance sampling from P-dist. to U-dist. Positive

$$R(f) = \pi \mathbb{E}_{p(\boldsymbol{x}|y=+1)} \left[\ell \left(f(\boldsymbol{x}) \right) + \frac{1 - r(\boldsymbol{x})}{r(\boldsymbol{x})} \ell \left(- f(\boldsymbol{x}) \right) \right]$$

$$\pi = p(y = +1) \quad r(\boldsymbol{x}) = P(y = +1|\boldsymbol{x})$$

$$R(f^*) - R(\widehat{f}) = \mathcal{O}_p(1/\sqrt{n})$$

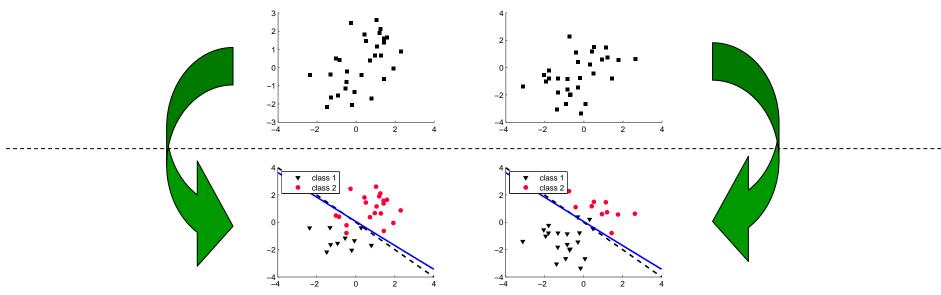
$$confidence$$

$$20\%$$

(2-4) UU Classification

du Plessis, Niu & Sugiyama (TAAI2013) Lu, Niu, Menon & Sugiyama (ICLR2019) Charoenphakdee, Lee & Sugiyama (ICML2019) Lu, Zhang, Niu & Sugiyama (AISTATS2020)

From two sets of unlabeled data with different class priors, PN classifiers are trainable by ERM!



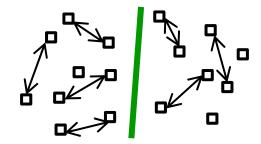
- In PU, we regarded U as noisy N.
- In UU, we use noisy P and noisy N!

$$\mathcal{O}_p\Big(1/\sqrt{n}\Big)$$

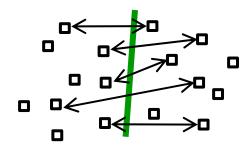
(2-5) SU Classification

Bao, Niu & Sugiyama (ICML2018)

- Delicate classification (money, religion...):
 - Highly hesitant to directly answer questions.
 - Less reluctant to just say "same as him/her".
- From similar data pairs and unlabeled data, $1/\sqrt{n}$ PN classifiers are trainable!



- Decoupling S-pairs results in UU classification!
- Learning from dissimilar data pairs is also possible.
 - SDU classification is also possible.



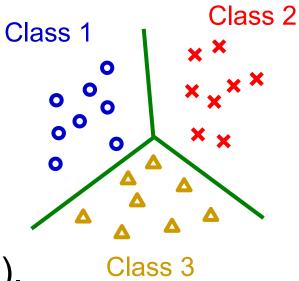
Ishida, Niu & Sugiyama (NIPS2017) Ishida, Niu, Menon & Sugiyama (ICML2019) Feng, Kaneko, Han, Niu, An & Sugiyama (ICML2020) Chou, Niu, Lin & Sugiyama (ICML2020)

Labeling patterns in multi-class problems:

 Selecting the collect class from a long class list is extremely painful.

Complementary labels:

 Specify a class that a pattern does not belong to ("not class 1").



- This is much easier and faster to collect!
- From complementary labels, classifiers are trainable by ERM!

 $1/\sqrt{n}$

Noisy labels with uniform transition to other classes.

Incorporating Ordinary Labels

Convert multiclass labeling into yes-no labeling:





https://www.bostondynamics.com/atlas

Is this Softbank Pepper? Yes! (ordinary label)

Is this iRobot Roomba?

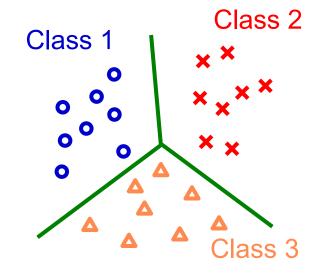
No! (complementary label)

Use both of ordinary and complementary labels!

$$R(f) = \mathbb{E}_{p(\boldsymbol{x},y)} \left[\mathcal{L} \left(f(\boldsymbol{x}), y \right) \right] + \left\{ (c-1) \mathbb{E}_{\bar{p}(\boldsymbol{x},\bar{y})} \left[\bar{\mathcal{L}} \left(f(\boldsymbol{x}), \bar{y} \right) \right] + \text{Const.} \right\}$$

(2-7) Partial-Label Classification ²²

- Partial label: Nguyen and Caruana (KDD2008)
 a subset of labels containing the true one
 - "Either 1 or 2"
 - Cheaper than ordinary labels
- From partial labels, classifiers are trainable by ERM!



 Complementary label is a special case of partial label.

Lv, Xu, Feng, Niu, Geng & Sugiyama (ICML2020) Feng, Lv, Han, Xu, Niu, Geng, An & Sugiyama (NeurlPS2020)



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Bias in Training Data

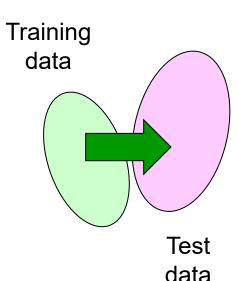
Quiñonero-Candela, Sugiyama, Schwaighofer & Lawrence (MIT Press 2009)

- Training and test data often have different distributions, due to
 - changing environments,
 - sample selection bias.
- Transfer learning/domain adaptation:
 - Match the distributions so that training data resemble test data.



Sugiyama & Kawanabe, Machine Learning in Non-Stationary Environments, MIT Press, 2012





Unsupervised Transfer Learning

- Given training input-output and test input, match the training and test distributions:
 - Better discrepancy measures for matching:

Kuroki, Charoenphakdee, Bao, Honda, Sato & Sugiyama (AAAl2019) Lee, Charoenphakdee, Kuroki & Sugiyama (arXiv2019)

Handling noisy labels in the source domain:

Liu, Lu, Han, Niu, Zhang & Sugiyama (arXiv2019)

- No/incomplete unlabeled data
 from the test domain:
 Ishii, Takenouchi & Sugiyama (MACV2020)
- Transferring data generation mechanism:

Teshima, Sato & Sugiyama (ICML2020) Teshima, Ishikawa, Tojo, Oono, Ikeda & Sugiyama (NeurIPS2020)

Simultaneous learning of a classifier and importance weights:

Zhang, Yamane, Lu & Sugiyama (ACML2020)
Fang, Lu, Niu & Sugiyama (NeurlPS2020)

(3-1) Mechanism Transfer

- Is transfer learning possible when data distributions are seemingly very different?
- Yes, if data generation mechanisms are shared:
 - Use invertible neural networks (INNs)

 Teshima, Sato & Sugiyama (ICML2020)

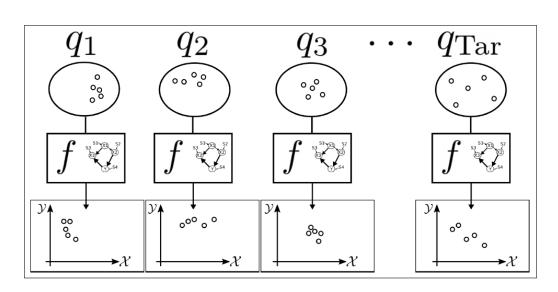
 to invert the data generation mechanism.
 - INNs are universal approximators.

Teshima, Ishikawa, Tojo, Oono, Ikeda & Sugiyama (NeurIPS2020)

Independent components

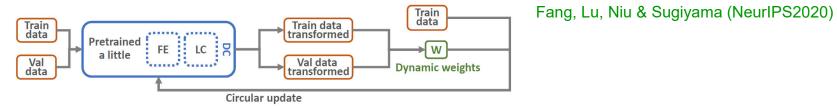
"Mechanism"

Observed data



(3-2) One-Step Adaptation

- Standard approach: 2 steps
 - Weight estimation: $\min_{w} D(w, p_{\mathrm{te}}/p_{\mathrm{tr}})$
 - Weighted classifier training: $\min_{f} \mathbb{E}_{p_{\mathrm{tr}}}[w(x,y)\ell(f(x),y)]$
- Proposed methods: 1 step
 - With a common feature extractor for w and f, learn them dynamically in mini-batch training.



• Minimize an upper bound of the risk w.r.t. w and f under covariate shift $p_{\rm tr}(y|x) = p_{\rm te}(y|x)$:

Zhang, Yamane, Lu & Sugiyama (ACML2020)

$$\min_{w,f} J(w,f) \quad J(w,f) \ge R^2(f)$$

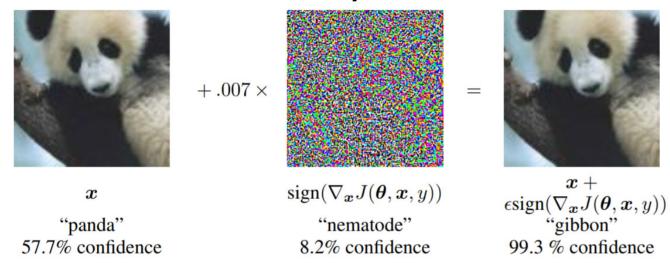


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Noise in Test Input

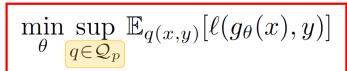
Neural nets are vulnerable to small perturbations in test input. Goodfellow et al. (ICLR2015)



- We want to be robust to such perturbations:
 - Robust to adversarial distribution shift.
 - "Friendly" adversarial training.
 - Defense to pointwise adversarial attack.
 - Rejection of adversarial data.

(4-1) Distributionally Robust Learning

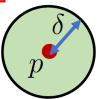
- Consider the worst-case test distribution when only training input-output is given:
- However, a naïve minimax approach does not work well:



$$Q_p = \{ q \mid D_f(q||p) \le \delta \}$$

"f-divergence ball"

[Bagnell 2005, Ben-Tal+ 2013, Namkoong+ 2016, 2017]



Proved to be non-robust for classification.

Hu, Niu, Sato & Sugiyama (ICML2018)

Elucidated the condition for loss calibration.

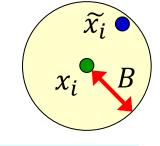
Bao, Scott & Sugiyama (COLT2020)

New formulation for being not too conservative.

Zhang, Xu, Han, Niu, Cui, Sugiyama & Kankanhalli (ICML2020)

(4-2) "Friendly" Adversarial Training 31

- Adversarial training:
 - Consider the worst test input.



$$\min_{f} \frac{1}{n} \sum_{i=1}^{n} \ell(f(\widetilde{x}_i), y_i) \qquad \widetilde{x}_i = \arg\max_{\widetilde{x} \in B(x_i)} \ell(f(\widetilde{x}), y_i)$$

$$\widetilde{x}_i = \underset{\widetilde{x} \in B(x_i)}{\operatorname{arg max}} \ell(f(\widetilde{x}), y_i)$$

- However, minimax training is too conservative.
- "Friendly" adversarial training:

Zhang, Xu, Han, Niu, Cui, Sugiyama & Kankanhalli (ICML2020)

 Among adversarial inputs, consider the one with certain margin ρ .

$$\widetilde{x_i} = \underset{\widetilde{x} \in B(x_i)}{\arg \min} \ \ell(f(\widetilde{x}), y_i)$$
s.t.
$$\ell(f(\widetilde{x}), y_i) - \underset{y}{\min} \ \ell(f(\widetilde{x}), y) \ge \rho$$

 Taking into account "geometry" can further Zhang, Zhu, Niu, Han, improve the robustness. Sugiyama & Kankanhalli (arXiv2020)

(4-3) Defense to Pointwise Attack³²

Stabilize output of the neural net:

$$\forall \epsilon, \left(\|\epsilon\|_2 < c \implies t_X = \operatorname*{argmax}_i \left\{ F\left(X + \epsilon\right)_i \right\} \right)$$

- Lipchitz-margin training:
- Tsuzuku, Sato & Sugiyama (NeurlPS2018)
- Compute the Lipchitz constant for each layer and for the entire network:

$$||F(X) - F(X + \epsilon)||_2 \le L_F ||\epsilon||_2$$

 Train the neural net to have large prediction margins:

$$\forall i \neq t_X, (F_{t_X} \geq F_i + \sqrt{2}cL_F)$$

Robustness is theoretically guaranteed.

(4-4) Classification with Reject Option

Ni, Charoenphakdee, Honda & Sugiyama (NeurlPS2019)

- In severe applications, better to reject difficult test inputs and ask human to predict instead.
- Approach 1: Train the classifier and rejector
 - Existing methods only focus on binary problems.
 - We proved this approach does not converge to the optimal solution generally in multi-class cases.
- Approach 2: Reject low-confidence prediction
 - Existing methods have limitation in loss functions (e.g., logistic loss), resulting in weak performance.
 - New rejection criteria for general losses with theoretical convergence guarantee.



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Summary

- Nowadays, ML systems are deployed in various societal problems, where reliability is extremely important.
- We explored robustness to different factors:
 - Noise: sensor error, human error
 - Insufficient information: weak supervision
 - Bias: sample selection bias, changing environments
 - Attack: adversarial noise, distribution shift

Challenges in Reliable ML

- Reliable ML in expectable situations:
 - Model the corruption process explicitly and correct the solution.
- Reliable ML in unexpected situations:
 - Consider worst-case robustness,
 - Include human support.
- Exploring somewhere in the middle would be practically useful and important.
 - Partial knowledge of the corruption process.

Challenges in Reliable ML

- In reliable ML research, the choice of performance metrics is crucial.
 - Simply improving the accuracy is not the goal.
- Since humans use ML systems, performance metrics should reflect human cognitive bias.
 - Ex: in image evaluation, MSE is not natural, but we care edges, texture, faces, etc.
- "Designing" appropriate performance metrics is an important challenge.

Past and Future of Al Research

Logical Al

- 1960's: Inference and search
- 1980's: Expert systems and knowledge bases

Neuro-inspired Al

- 1960's: Single-layer perceptrons
- 1990's: Multi-layer perceptrons

Statistical ML based Al

- 2000's: Frequentist statistics, convex optimization, Bayesian statistics
 - 2010's: Deep learning

Future Al

Human-like AI? Human-inclusive AI?